

Search Notes

Application/Control No.

10/687,096

Examiner

Sara W. Crane

Applicant(s)/Patent under Reexamination

VOELZ, JAMES L.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	669	4/05	SWC
update		5/06	SWC
update		11/06	SWC
438	114		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

EAST	DATE	EXMR
(backside adj coating) and wafer, printed circuit, (wafer adj scale)	4/05	SWC
update see printout	5/06	SWC
see printout	11/06	SWC